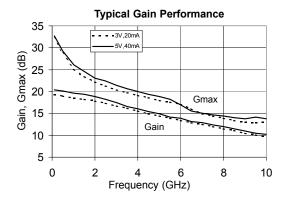


# **Product Description**

Stanford Microdevices' SPF-3043 is a high performance 0.25μm pHEMT Gallium Arsenide FET. This 300μm device is ideally biased at 3V,20mA for lowest noise performance and battery powered requirements. At 5V,40mA the device delivers excellent OIP3 of 32dBm. It provides ideal performance as a driver stage in many commercial and industrial LNA applications.



# **SPF-3043**

### Low Noise pHEMT GaAs FET

Qualification Pending April 2001



### **Product Features**

DC-10 GHz Operation

**Ultra Low NF:** 0.25 dB @ 1 GHz

0.50 dB @ 2 GHz

High Assoc. Gain: 25 dB @ 1 GHz

22 dB @ 2 GHz

Low Current Draw for NFopt (3V,20mA)

+32 dBm OIP3, +20 dBm P1dB (5V,40mA)

Low Cost High Performance pHEMT

# **Applications**

- **LNA for Wireless Infrastructure**
- **Fixed Wireless Infrastructure**
- Wireless Data
- **Driver Stage for Low Power Applications**

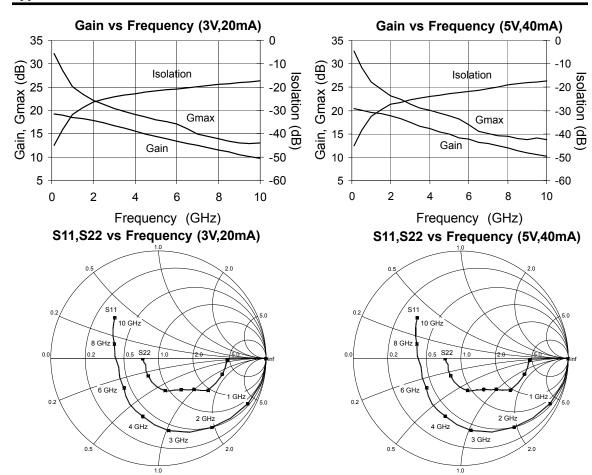
Symbol	Device Characteristics, T = 25°C V <sub>DS</sub> =3V, I <sub>DS</sub> =20mA (unless otherwise noted)		Units	Min.	Тур.	Max.
$G_{\scriptscriptstyle{MAX}}$	Maximum Available Gain $Z_s=Z_s^*$ , $Z_t=Z_t^*$	f = 0.9 GHz f = 1.9 GHz	dB		25.5 22.4	
S <sub>21</sub>	Insertion Gain $Z_s=Z_z=50\Omega$	f = 0.9 GHz f = 1.9 GHz	dB		18.5 18.0	
NF <sub>min</sub>	Minimum Noise Figure $Z_s = \Gamma_{OPT}$ , $Z_t = Z_t^*$	f = 0.9 GHz f = 1.9 GHz	dB		0.25 0.50	
P1dB	Output 1 dB compression point $Z_s = Z_{SOPT}$ , $Z_t = Z_{LOPT}$	V <sub>DS</sub> =3V, I <sub>DS</sub> =20 mA V <sub>DS</sub> =5V, I <sub>DS</sub> =40 mA	dBm		15.5 20	
OIP <sub>3</sub>	Output Third Order Intercept Point $Z_s = Z_{SOPT}$ , $Z_t = Z_{LOPT}$	V <sub>DS</sub> =3V, I <sub>DS</sub> =20 mA V <sub>DS</sub> =5V, I <sub>DS</sub> =40 mA	dBm		29 32	
V <sub>P</sub>	Pinchoff Voltage	V <sub>DS</sub> = 2V, I <sub>DS</sub> = 0.1 mA	V	-1.1	-0.8	-0.5
I <sub>DSS</sub>	Saturated Drain Current	V <sub>DS</sub> = 2V, V <sub>GS</sub> = 0V	mA	45	67.5	100
g <sub>mp</sub>	Peak Transconductance	V <sub>DS</sub> = 2V, V <sub>GS</sub> @ g <sub>mp</sub>	mS	100	150	
BV <sub>GSO</sub>	Gate-to-Source Breakdown Voltage	I <sub>s</sub> = 0.03 mA Drain Open, Source Grounded	V		-10	-8
BV <sub>GDO</sub>	Gate-to-Drain Breakdown Voltage	I <sub>c</sub> = 0.03 mA Source Open, Drain Grounded	V		-10	-8
Rth	Thermal Resistance (junction to lead)		°C/W		150	

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## Typical Performance



Note: S-parameters are de-embedded to the device leads with  $Z_s = Z_L = 50\Omega$ . The data represents typical performace of the device. De-embedded s-parameters can be downloaded from our website (www.stanfordmicro.com).

### Typical Performance

Freq (MHz)	V <sub>DS</sub> (V)	I <sub>DS</sub> (mA)	Fmin (dB)	Γ <sub>οΡΤ</sub> Mag ∠ Ang	r <sub>N</sub>	Gmax (dB)	P1dB (dBm)	OIP3 (dBm)
900	3	20	0.25	0.79 ∠ 12	0.22	25.5	15.5	29
900	5	40	0.32	0.75 ∠ 12	0.25	26.5	20.0	32
1000	3	20	0.50	0.62 ∠ 34	0.19	22.4	15.5	29
1900	5	40	0.54	0.62 ∠ 33	0.20	23.3	20.0	32



### **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Drain Current	I <sub>DS</sub>	150	mA
Forward Gate Current	l <sub>GS</sub>	2	mA
Drain-to-Source Voltage	V <sub>DS</sub>	7	V
Gate-to-Source Voltage	$V_{\rm GS}$	-3	V
RF Input Power	P <sub>N</sub>	15	dBm
Operating Temperature	T <sub>OP</sub>	-40 to +85	С
Storage Temperature Range	T <sub>stor</sub>	-40 to +150	С
Power Dissipation	P <sub>DISS</sub>	430	mW
Operating Junction Temperature	T <sub>J</sub>	+150	С

### Caution: ESD sensitive

Appropriate precautions in handling, packaging and testing devices must be observed.

### SPF-3043 Low Noise pHEMT GaAs FET

### **Part Number Ordering Information**

Part Number	Reel Size	Devices/Reel
SPF-3043	7"	3000

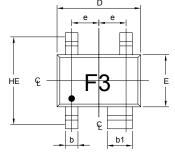
### Part Symbolization

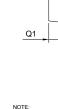
The part will be symbolized with an "F3" and a Pin 1 indicator on the top surface of the package.

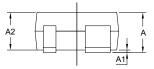
### **Pin Description**

Pin #	Function	Description
1	Gate	RF Input
2	GND & Source	Connection to ground. Use via holes to reduce lead inductance. Place vias as close to ground leads as possible.
3	Drain	RF Output
4	GND & Source	Same as Pin 2









- 1. ALL DIMENSIONS ARE IN MILLIMETERS
- 2. DIMENSIONS ARE INCLUSIVE OF PLATING 3. DIMENSIONS ARE EXCLUSIVE OF MOLD FLASH

С

- & METAL BURR
- 5. DIE IS FACING UP FOR MOLD AND FACING DOWN FOR TRIM/FORM. ie :REVERSE TRIM/FORM.
- 6. PACKAGE SURFACE TO BE MIRROR FINISH.

4	3
1	2

SYMBOL	MIN	MAX
E	1.15	1.35
D	1.85	2.25
HE	1.80	2.40
Α	0.80	1.10
A2	0.80	1.00
A1	0.00	0.10
Q1	0.10	0.40
е	0.65 BSC	
b	0.25	0.40
b1	0.55	0.70
С	0.10	0.18
_	0.10	0.30

Use multiple plated-through vias holes located close to the package pins to ensure a good RF ground connection to a continuous groundplane on the backside of the board.